

TELECOMMUNICATION SYSTEM SECONDARY PROTECTION

- **Ion-Implanted Breakdown Region**
Precise and Stable Voltage
Low Voltage Overshoot under Surge

DEVICE	$V_{(Z)}$ V	$V_{(BO)}$ V
'2290	200	290

- **Planar Passivated Junctions**
Low Off-State Current < 10 μ A
- **Rated for International Surge Wave Shapes**

WAVE SHAPE	STANDARD	I_{TSP} A
8/20 μ s	ANSI C62.41	150
10/160 μ s	FCC Part 68	60
10/560 μ s	FCC Part 68	45
0.2/310 μ s	RLM 88	38
10/700 μ s	FTZ R12	50
	VDE 0433	50
	CCITT IX K17/K20	50
10/1000 μ s	REA PE-60	50

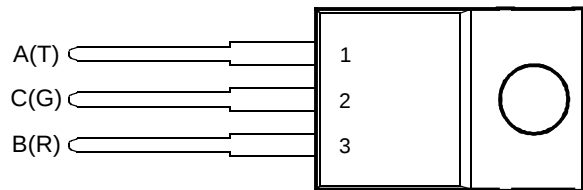
- **UL Recognized, E132482**

description

The TISP2290 is designed specifically for telephone equipment protection against lightning and transients induced by a.c. power lines. These devices will suppress voltage transients between terminals A and C, B and C, and A and B.

Transients are initially clipped by zener action until the voltage rises to the breakover level, which causes the device to crowbar. The high crowbar holding current prevents d.c. latchup as the transient subsides.

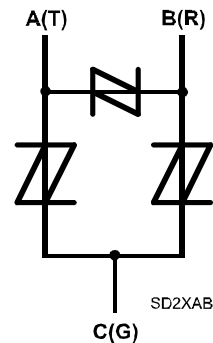
TO-220 PACKAGE
(TOP VIEW)



Pin 2 is in electrical contact with the mounting base.

MDXXANA

device symbol



These monolithic protection devices are fabricated in ion-implanted planar structures to ensure precise and matched breakover control and are virtually transparent to the system in normal operation.

PRODUCT INFORMATION

Information is current as of publication date. Products conform to specifications in accordance with the terms of Power Innovations standard warranty. Production processing does not necessarily include testing of all parameters.

TISP2290

DUAL SYMMETRICAL TRANSIENT VOLTAGE SUPPRESSORS

NOVEMBER 1986 - REVISED SEPTEMBER 1997

absolute maximum ratings at 25°C case temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT
Non-repetitive peak on-state pulse current (see Notes 1, 2 and 3)	I_{TSP}	150	A
8/20 μ s (ANSI C62.41, open-circuit voltage wave shape 1.2/50 μ s)		60	
10/160 μ s (FCC Part 68, open-circuit voltage wave shape 10/160 μ s)		50	
5/200 μ s (VDE 0433, open-circuit voltage wave shape 2 kV, 10/700 μ s)		38	
0.2/310 μ s (RLM 88, open-circuit voltage wave shape 1.5 kV, 0.5/700 μ s)		50	
5/310 μ s (CCITT IX K17/K20, open-circuit voltage wave shape 2 kV, 10/700 μ s)		50	
5/310 μ s (FTZ R12, open-circuit voltage wave shape 2 kV, 10/700 μ s)		45	
10/560 μ s (FCC Part 68, open-circuit voltage wave shape 10/560 μ s)		50	
10/1000 μ s (REA PE-60, open-circuit voltage wave shape 10/1000 μ s)			
Non-repetitive peak on-state current, 50 Hz, 2.5 s (see Notes 1 and 2)	I_{TSM}	10	A rms
Initial rate of rise of on-state current, Linear current ramp, Maximum ramp value < 38 A	di_T/dt	250	A/ μ s
Junction temperature	T_J	150	°C
Operating free - air temperature range		0 to 70	°C
Storage temperature range	T_{stg}	-40 to +150	°C
Lead temperature 1.5 mm from case for 10 s	T_{lead}	260	°C

- NOTES: 1. Above 70°C, derate linearly to zero at 150°C case temperature
2. This value applies when the initial case temperature is at (or below) 70°C. The surge may be repeated after the device has returned to thermal equilibrium.
3. Most PTT's quote an unloaded voltage waveform. In operation the TISP essentially shorts the generator output. The resulting loaded current waveform is specified.

electrical characteristics for the A and B terminals, $T_J = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_Z Reference zener voltage	$I_Z = \pm 1\text{mA}$	± 200			V
I_D Off-state leakage current	$V_D = \pm 50\text{V}$			± 10	μA
C_{off} Off-state capacitance	$V_D = 0$ $f = 1\text{kHz}$ (see Note 4)		40	100	pF

NOTE 4: These capacitance measurements employ a three terminal capacitance bridge incorporating a guard circuit. The third terminal is connected to the guard terminal of the bridge.

electrical characteristics for the A and C or the B and C terminals, $T_J = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_Z Reference zener voltage	$I_Z = \pm 1\text{mA}$	± 200			V
αV_Z Temperature coefficient of reference voltage			0.1		%/°C
$V_{(BO)}$ Breakover voltage	(see Notes 5 and 6)			± 290	V
$I_{(BO)}$ Breakover current	(see Note 5)	± 0.15		± 0.6	A
V_{TM} Peak on-state voltage	$I_T = \pm 5\text{A}$ (see Notes 5 and 6)		± 1.9	± 3	V
I_H Holding current	(see Note 5)	± 150			mA
dv/dt Critical rate of rise of off-state voltage	(see Note 7)			± 5	kV/ μ s
I_D Off-state leakage current	$V_D = \pm 50\text{V}$			± 10	μA
C_{off} Off-state capacitance	$V_D = 0$ $f = 1\text{kHz}$ (see Note 4)		110	200	pF

- NOTES: 5. These parameters must be measured using pulse techniques, $t_w = 100\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
6. These parameters are measured with voltage sensing contacts separate from the current carrying contacts located within 3.2 mm (0.125 inch) from the device body.
7. Linear rate of rise, maximum voltage limited to 80 % V_Z (minimum)..

PRODUCT INFORMATION

PARAMETER MEASUREMENT INFORMATION

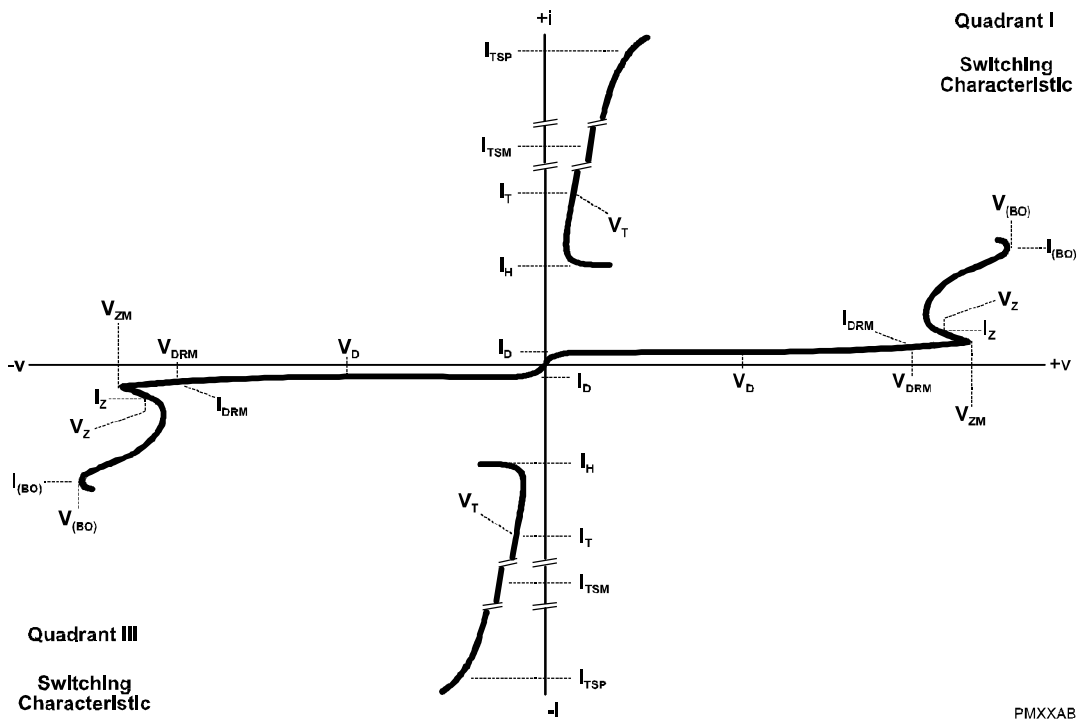


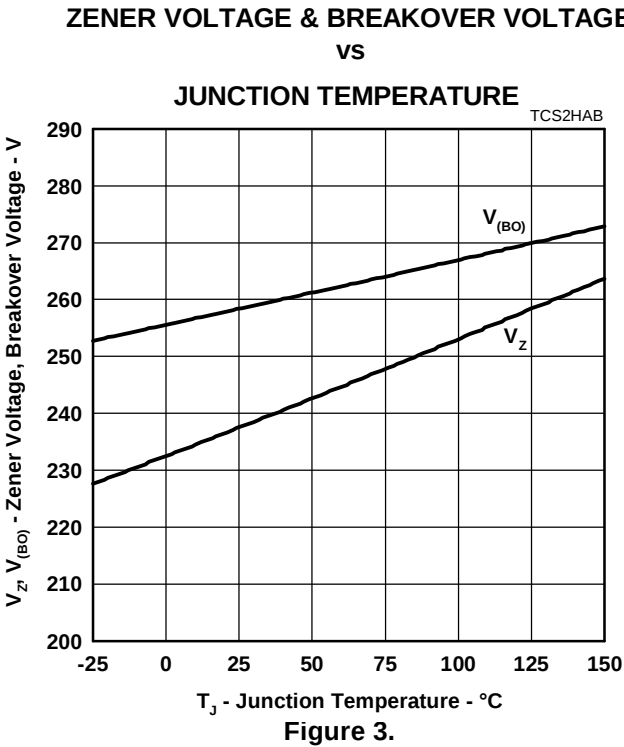
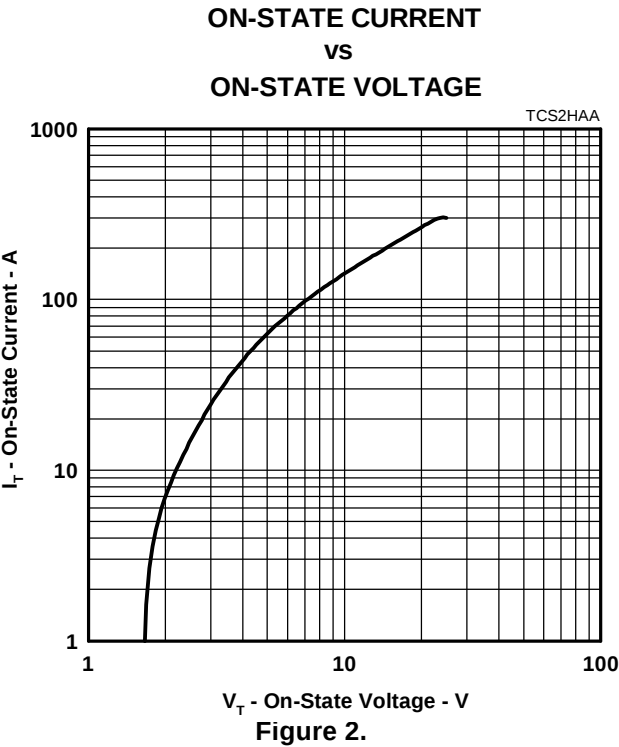
Figure 1. VOLTAGE-CURRENT CHARACTERISTIC FOR ANY PAIR OF TERMINALS

The high level characteristics for terminals A and B are not guaranteed.

thermal characteristics

PARAMETER		MIN	TYP	MAX	UNIT
$R_{\theta JA}$	Junction to free air thermal resistance			62.5	°C/W

TYPICAL CHARACTERISTICS
A and C, or B and C terminals



TYPICAL CHARACTERISTICS A and C, or B and C terminals

**HOLDING CURRENT & BREAKOVER CURRENT
VS**

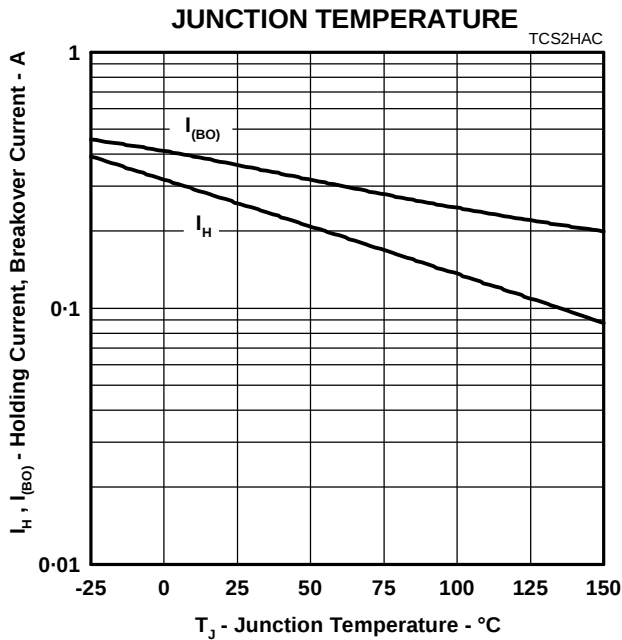


Figure 4.

**OFF-STATE CURRENT
VS**

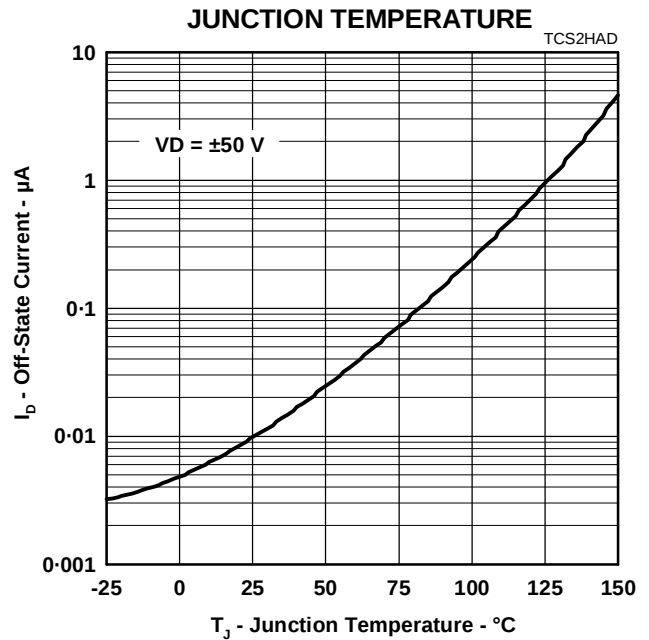


Figure 5.

**ON-STATE VOLTAGE
VS**

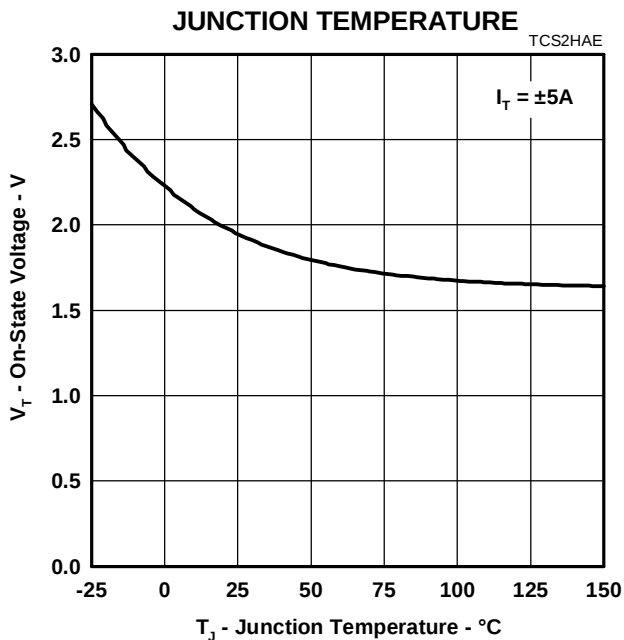


Figure 6.

**NORMALISED BREAKOVER VOLTAGE
VS**

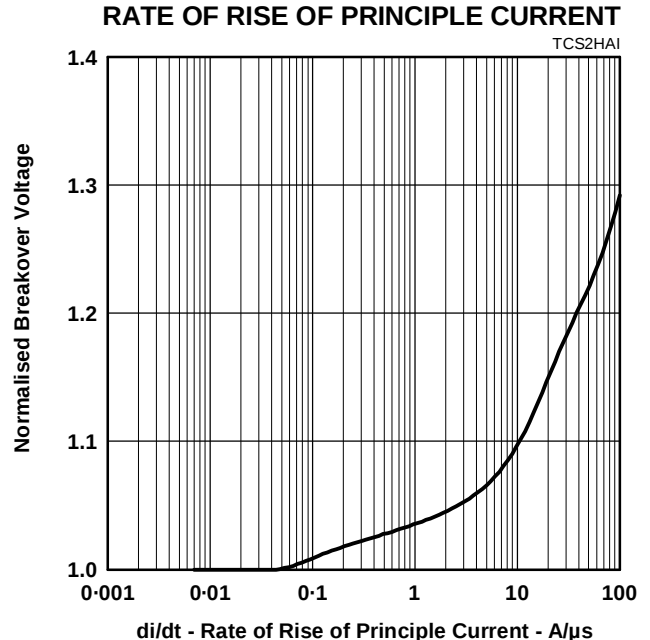
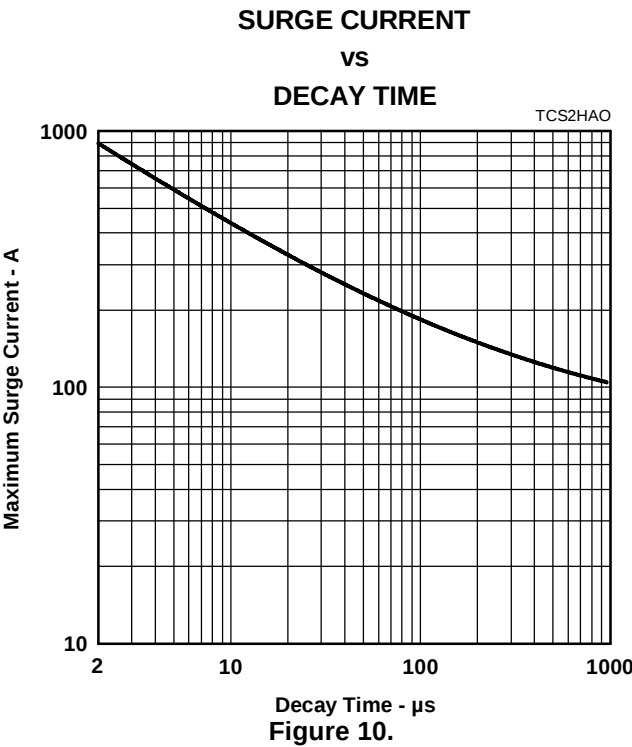
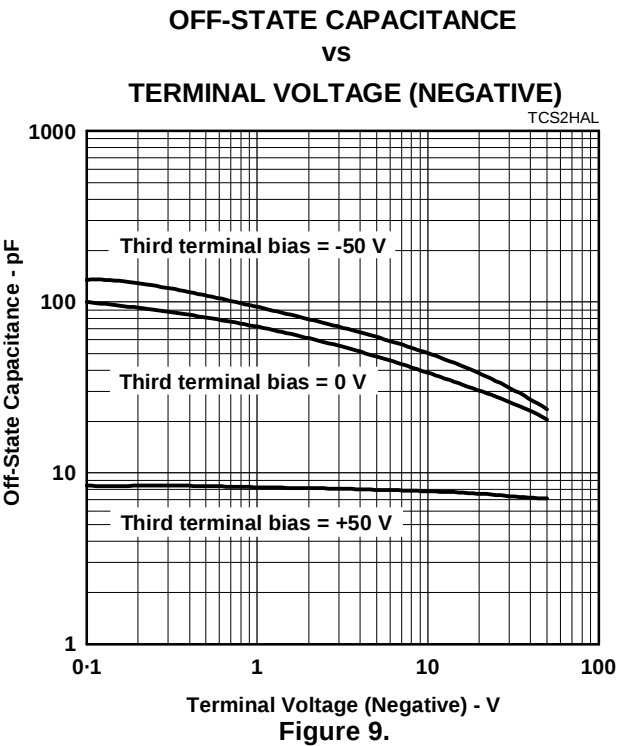
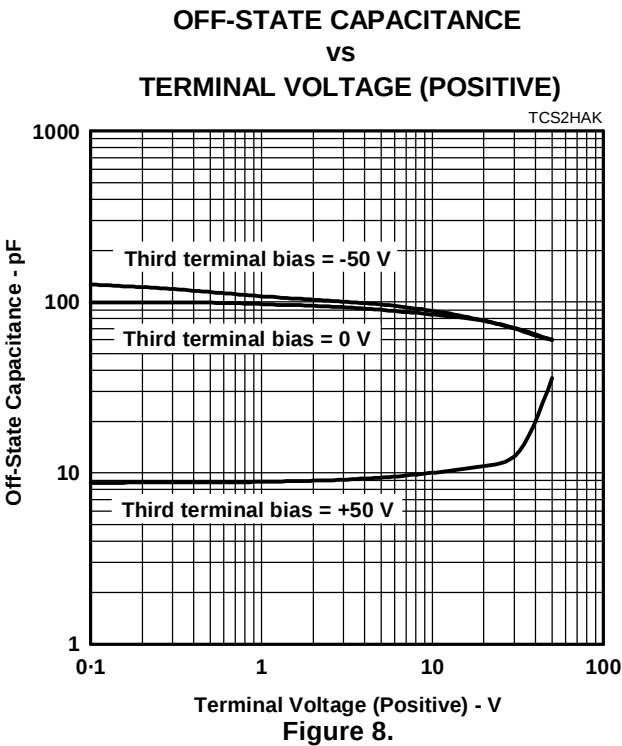


Figure 7.

TYPICAL CHARACTERISTICS
A and C, or B and C terminals



TYPICAL CHARACTERISTICS A and B terminals

ZENER VOLTAGE & BREAKOVER VOLTAGE VS

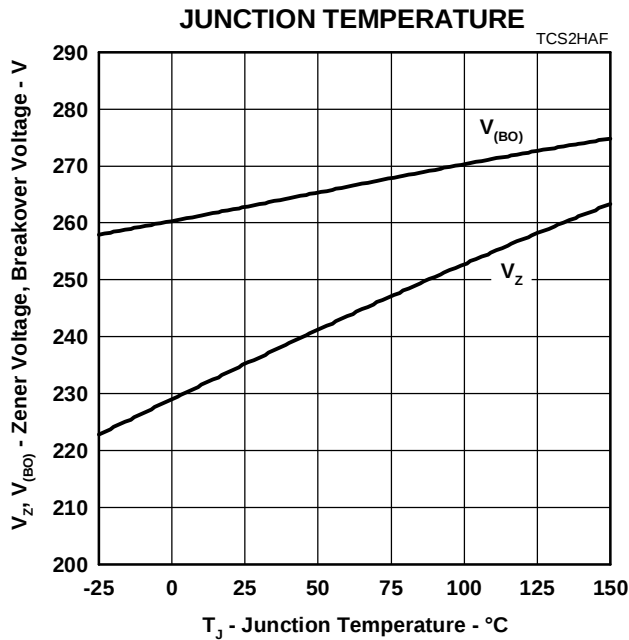


Figure 11.

HOLDING CURRENT & BREAKOVER CURRENT VS

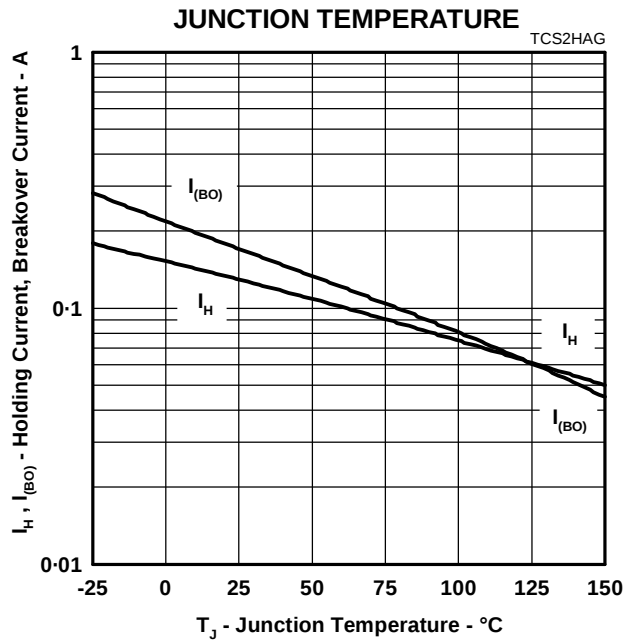


Figure 12.

OFF-STATE CURRENT VS

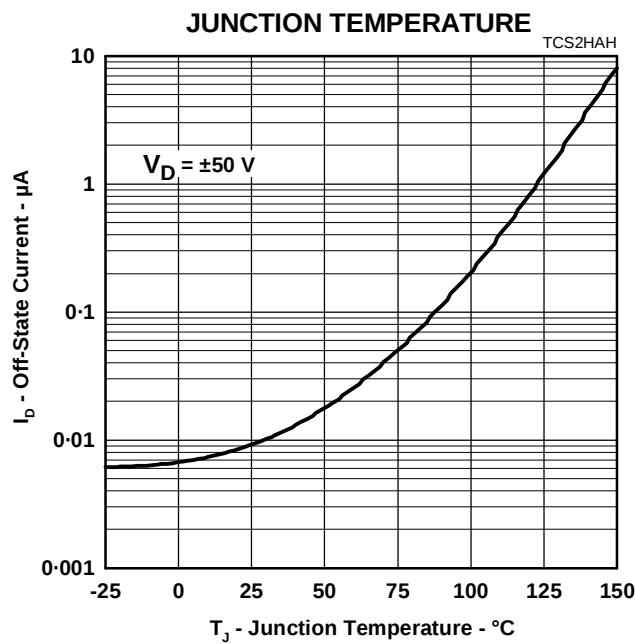
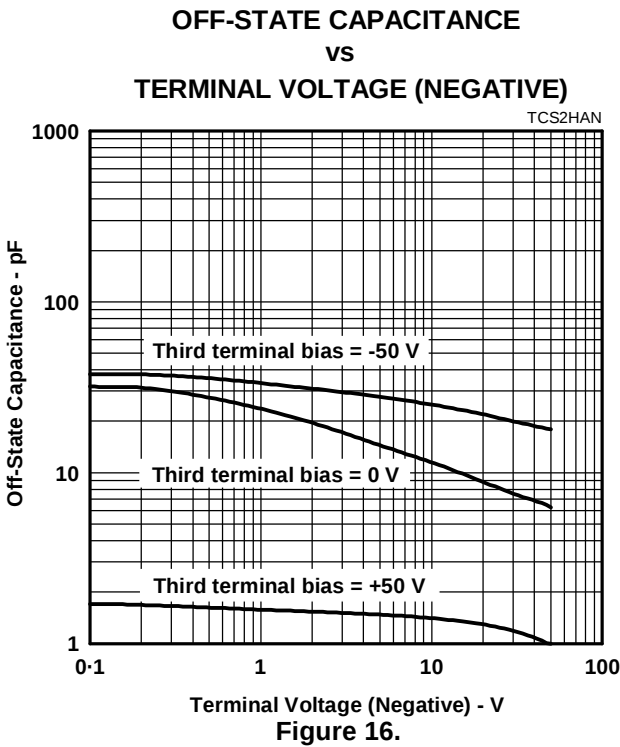
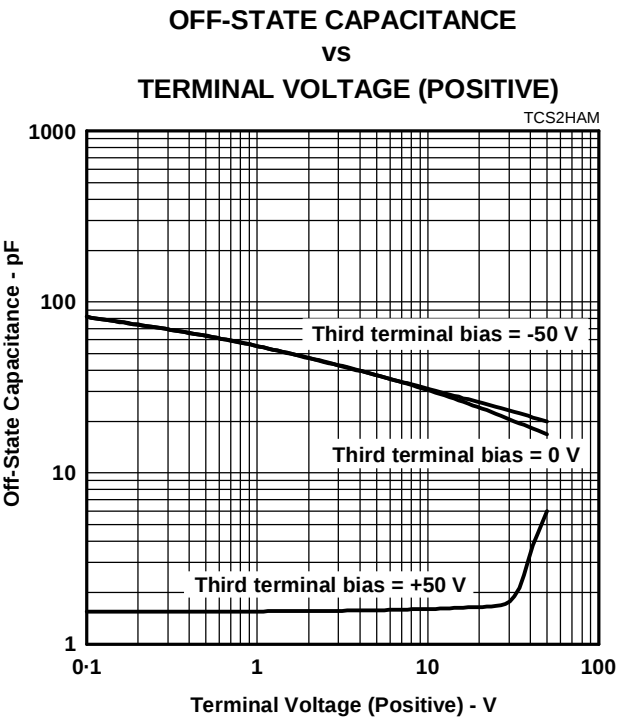
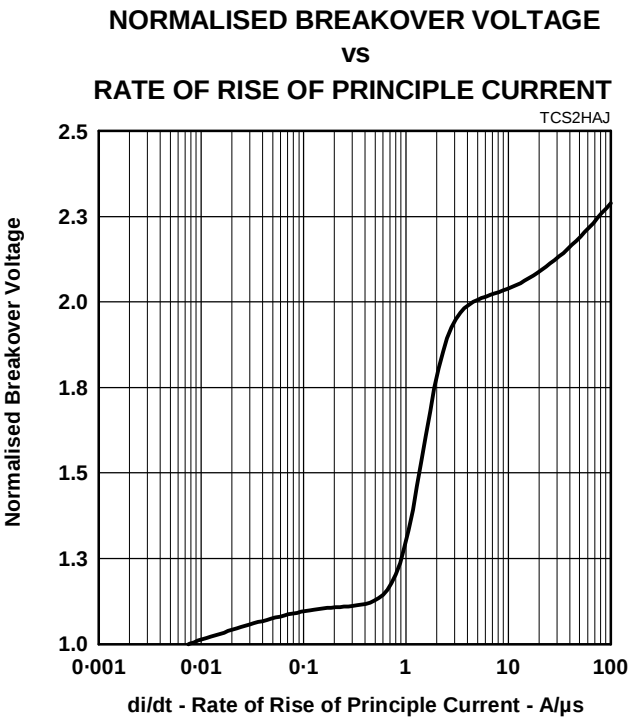


Figure 13.

TYPICAL CHARACTERISTICS
A and B terminals



THERMAL INFORMATION

THERMAL RESPONSE

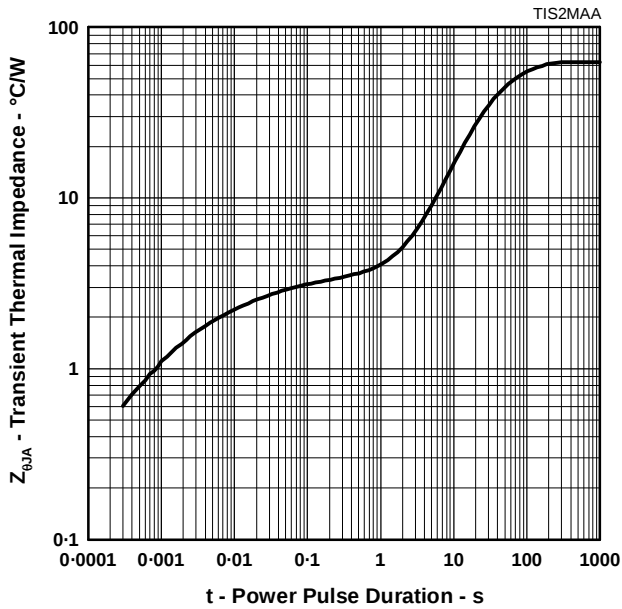


Figure 17.

**MAXIMUM NON-RECURRENT 50Hz CURRENT
 VS
 CURRENT DURATION**

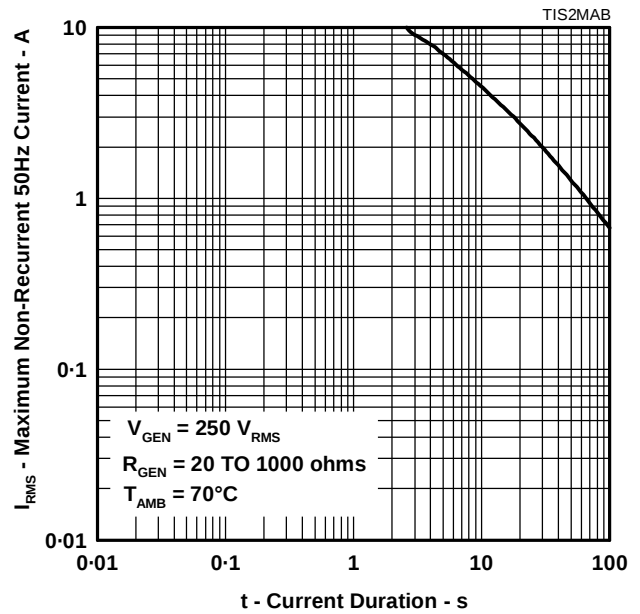


Figure 18.

FREE AIR TEMPERATURE

DERATING CURVE

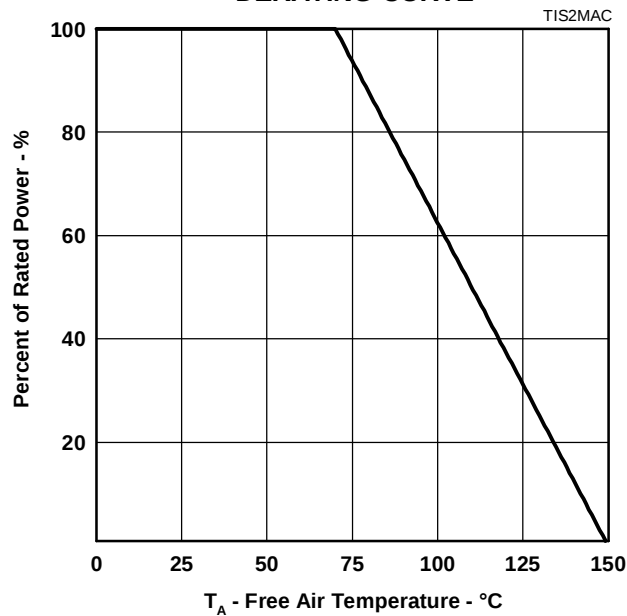
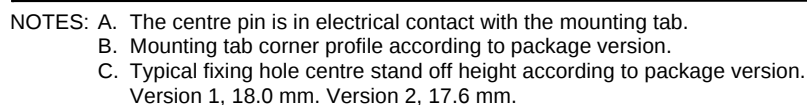


Figure 19.

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TO-220

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



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